

**Search Notes**

Application/Control No.

10/602,462

Examiner

Tianjie Chen

Applicant(s)/Patent under  
Reexamination

BEDELL ET AL.

Art Unit

2627

**SEARCHED**

Class	Subclass	Date	Examiner
Updated		9/17/2007	TJ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR